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INFORMATION DISCLOSURE STATEMENT TRANSMITTAL To Commissioner For Patents Enclosed herewith is a Form PTO-1449, any required copies of documents listed thereon, and any concise explanation of their relevance is indicated below per 37 CFR 1.97.	Application Number	10/586218
	Filing Date	
	First Named Inventor	MARINISSEN, ERIK J.
	Group Art Unit	2117
	Examiner Name	JAMES C KERVEROS
	Atty. Docket Number	NL040065US1

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number No.-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns Lines, Where Relevant Passages or Relevant Figures Appear
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FOREIGN PATENT DOCUMENTS						
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NON-PATENT LITERATURE DOCUMENTS					
Examiner Initials*	Cite No. ¹	Include name of the author (in capital letters), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			T ³
	1	WAAYERS T ED - INSTITUTE OF ELECTRICAL AND ELECTRONICS ENGINEERS: "AN IMPROVED TEST CONTROL ARCHITECTURE AND TEST CONTROL EXPANSION FOR CORE-BASED SYSTEM CHIPS"; PROCEEDINGS INTERNATIONAL TEST CONFERENCE 2003. (ITC); CHARLOTTE NC. SEPT. 30, OCT. 2, 2003; INTERNATIONAL TEST CONF. N.Y.: IEEE US VOL. 1, 30 SEPT 2003; PP 1145-1154			
	2	ZORIAN Y ET AL: "TESTING EMBEDDED-CORE BASED SYSTEM CHIPS"; PROCEEDINGS INTERNATIONAL TEST CONFERENCE 1998 (IEEE CAT. NO. 98CH36270) INT. TEST CONF. WASHINGTON DC USA; ONLINE 23 OCT. 1998 (1998-10-23) PP 130-143.			

Examiner Signature	/James Kerveros/	Date Considered	05/27/2008
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